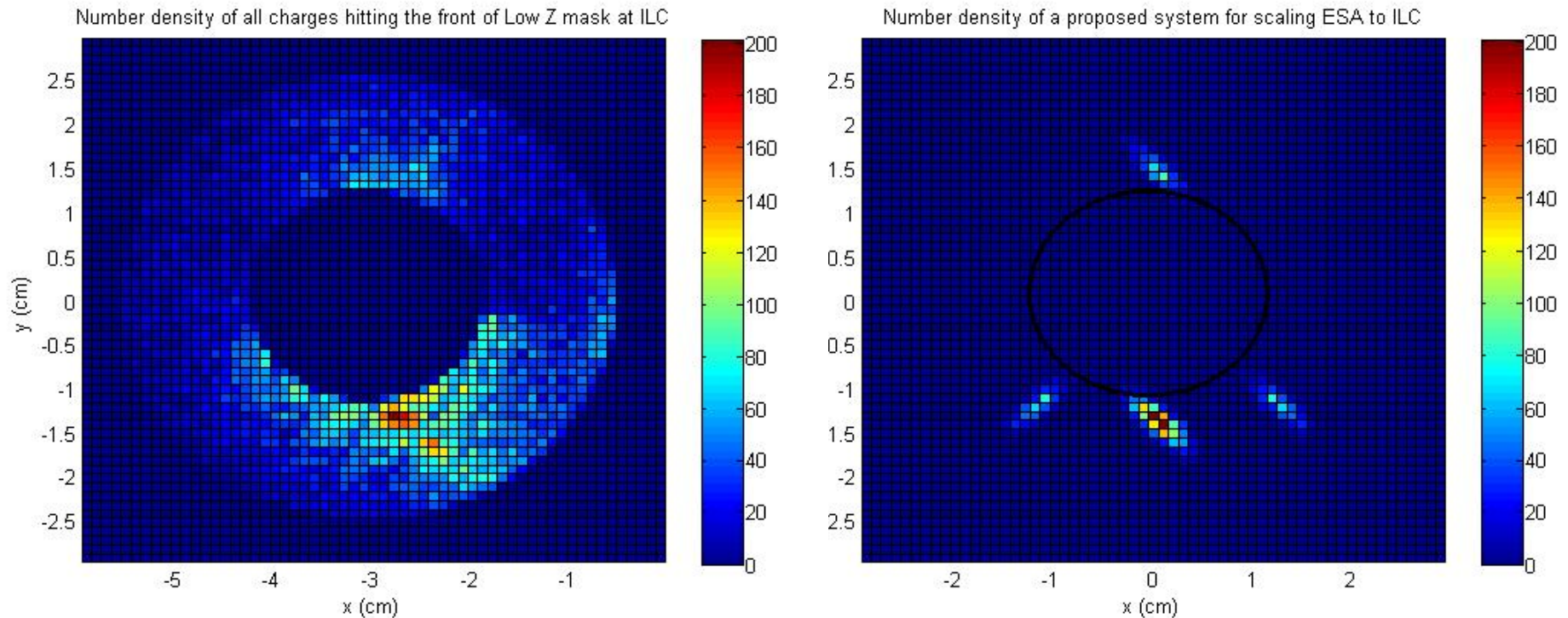


At ESA we had a spot size  $\sigma_x$  2100 $\mu\text{m}$  and  $\sigma_y$  700 $\mu\text{m}$ . It was positioned at various radii either directed at a stripline or inbetween two striplines. Currents were of the order  $5e6$  electrons per bunch.

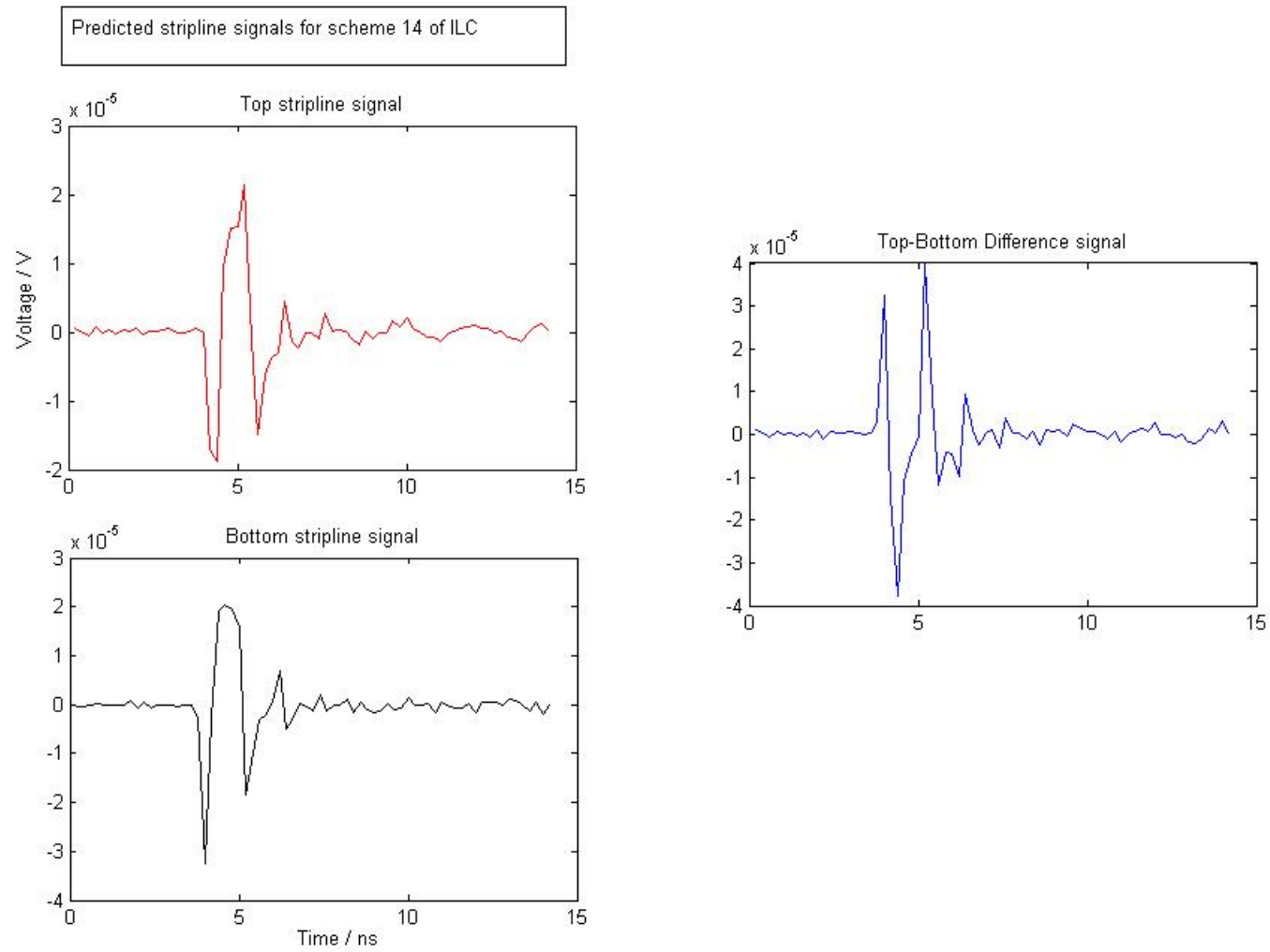
How can I scale to ILC conditions?

1. Match Number Density of charges
2. Match Number of charges – NEW

Here I note that there are more charges at the top and around the bottom edge and match number densities in these four patches.

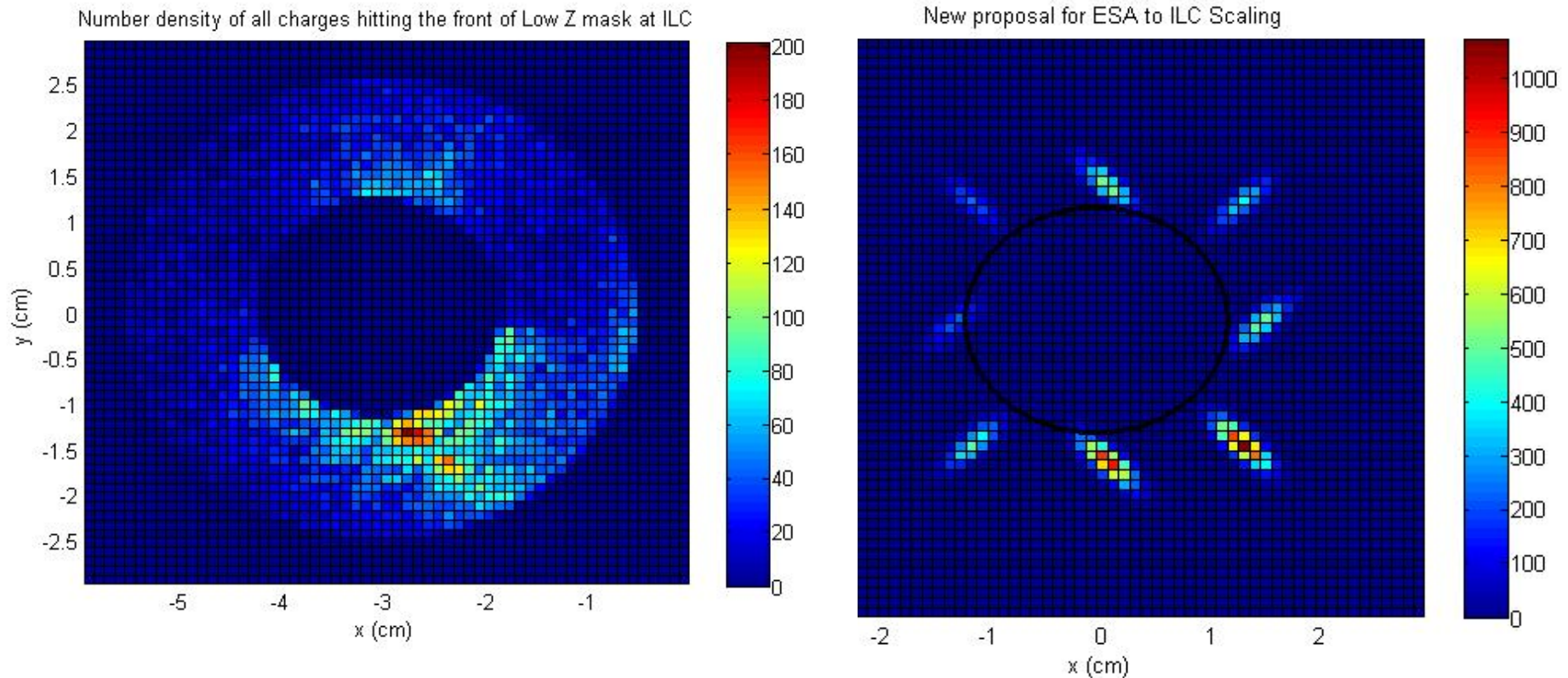


From associating the patches to runs in ESA, I can superimpose stripline signals to build up a prediction of signals for ILC conditions.

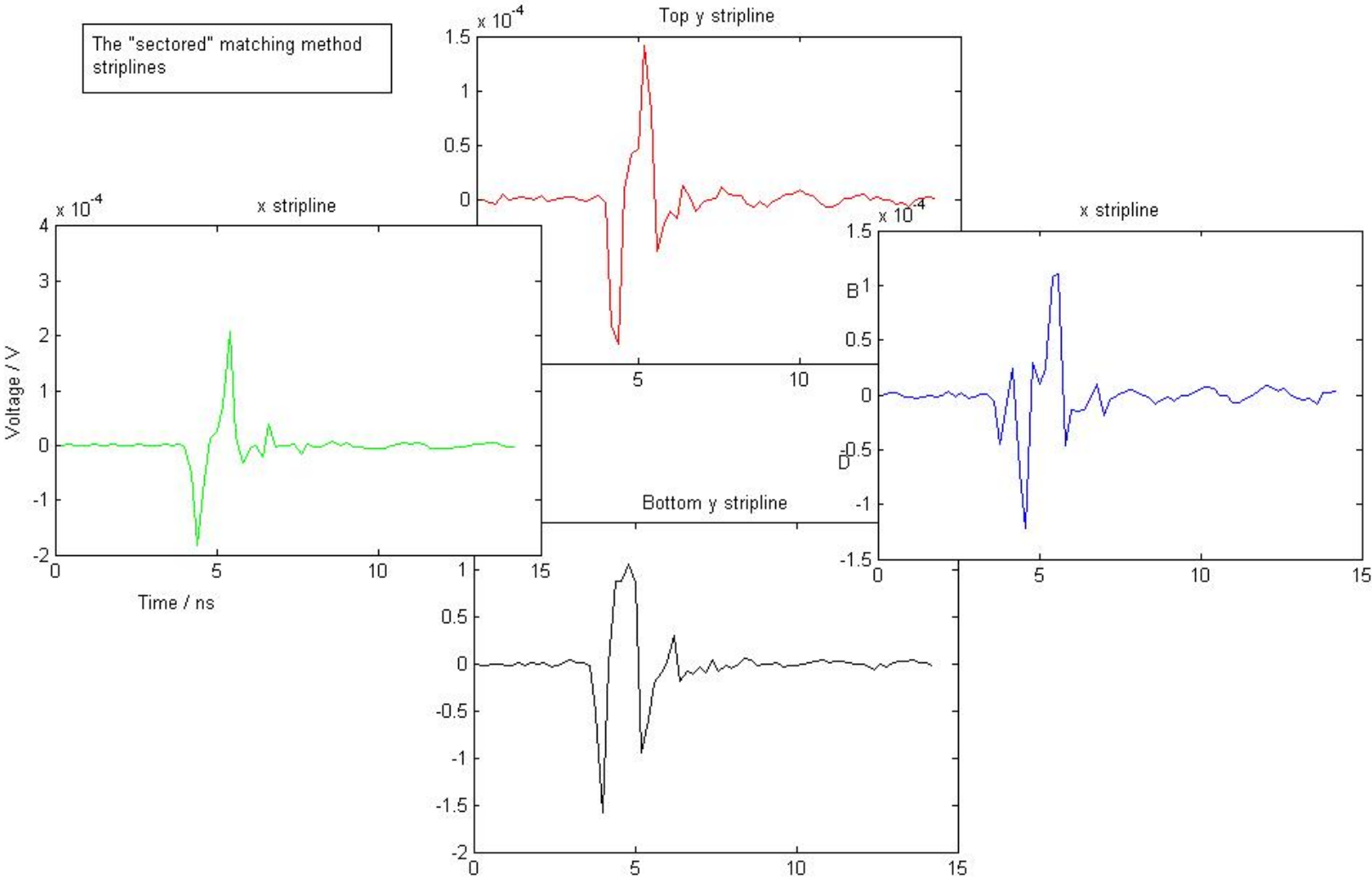


As I have only used “patches”, I only have a tenth of the actual flux hitting the Low Z.

“Sector” method- I sum the charges in eight sectors around the Low Z. I use eight ESA runs to match the number of charges. As the spot size at ESA was small, this leads to a higher number density at each point but the total flux hitting the mask matches ILC.



Again, I can superimpose stripline signals to build up a prediction of signals for ILC conditions.



This gives me a factor of ten greater difference than the other method.

How does this compare to the difference for  $2e10$  electron beam offset by a micron?

